

## 5.0A Leaded Type Fast Recovery Effciency Rectifiers-50V-1000V

### Package outline

**DO-201AD**

### Features

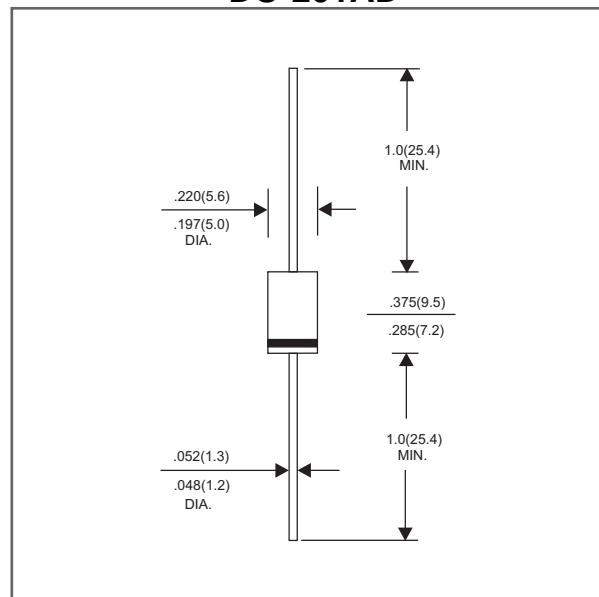
- Axial lead type devices for through hole design.
- 5.0A operating at TA=55°C without thermal run away
- High current capability.
- Ultrafast recovery time for high efficiency.
- High surge capability.
- Glass passivated chip junction.
- Lead-free parts meet RoHS requirements.
- Suffix "-H" indicates Halogen free parts, ex. HER501G-H.

### Mechanical data

- Epoxy : UL94-V0 rated flame retardant
- Case : Molded plastic, DO-201AD
- Lead: Axial leads, solderable per MIL-STD-202,

Method 208 guaranteed

- Polarity: Color band denotes cathode end
- Mounting Position : Any
- Weight : Approximated 1.10 gram



Dimensions in inches and (millimeters)

### Maximum ratings (AT $T_A=25^\circ\text{C}$ unless otherwise noted)

PARAMETER	CONDITIONS	Symbol	MIN.	TYP.	MAX.	UNIT
Forward rectified current	Ambient temperature = 50°C	$I_o$			5.0	A
Forward surge current	8.3ms single half sine-wave superimposed on rate load (JEDEC method)	$I_{FSM}$			200	A
Reverse current	$V_R = V_{RRM} T_J = 25^\circ\text{C}$	$I_R$		5.0		$\mu\text{A}$
	$V_R = V_{RRM} T_J = 125^\circ\text{C}$				100	
Diode junction capacitance	f=1MHz and applied 4V DC reverse voltage	$C_J$		75		pF
Storage temperature		$T_{STG}$	-65		+175	°C

SYMBOLS	$V_{RRM}^{*1}$ (V)	$V_{RMS}^{*2}$ (V)	$V_R^{*3}$ (V)	$V_F^{*4}$ (V)	$T_{RR}^{*5}$ (nS)	Operating temperature $T_J$ , (°C)
HER501G	50	35	50			
HER502G	100	70	100	1.00		
HER503G	200	140	200			
HER504G	300	210	300			
HER505G	400	280	400	1.30		
HER506G	600	420	600			
HER507G	800	560	800			
HER508G	1000	700	1000	1.85	75	

\*1 Repetitive peak reverse voltage

\*2 RMS voltage

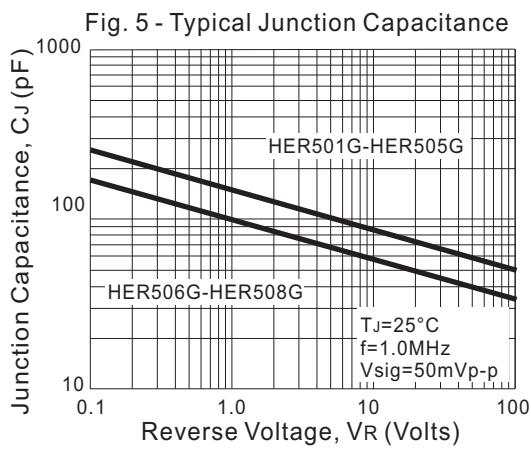
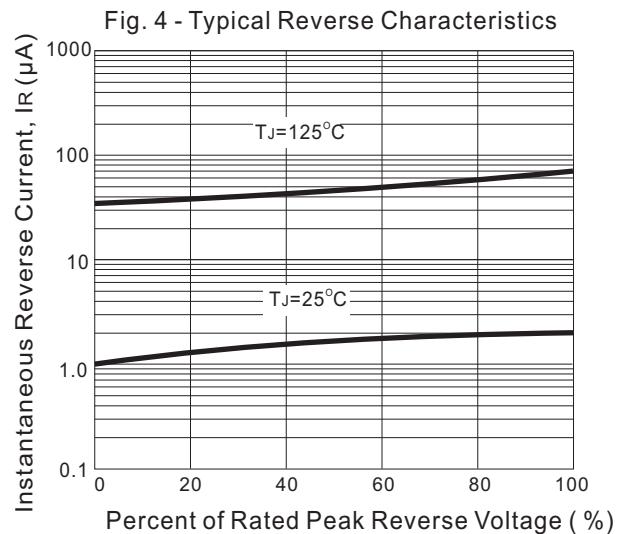
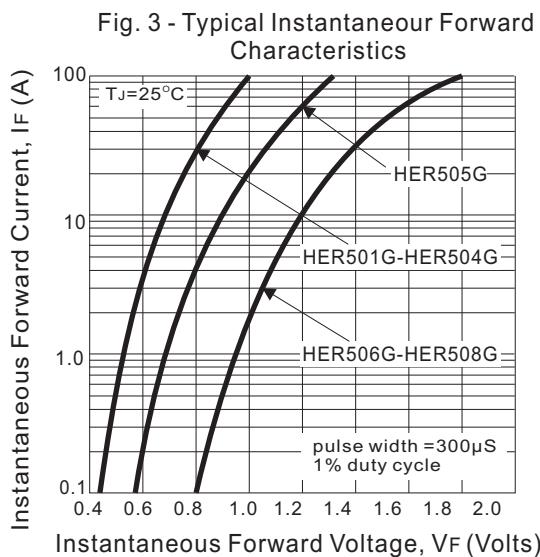
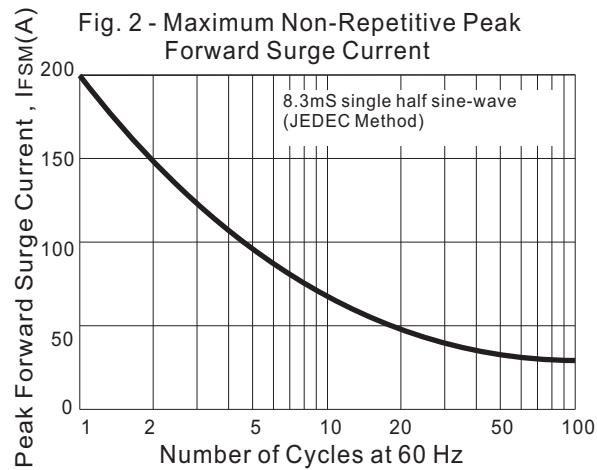
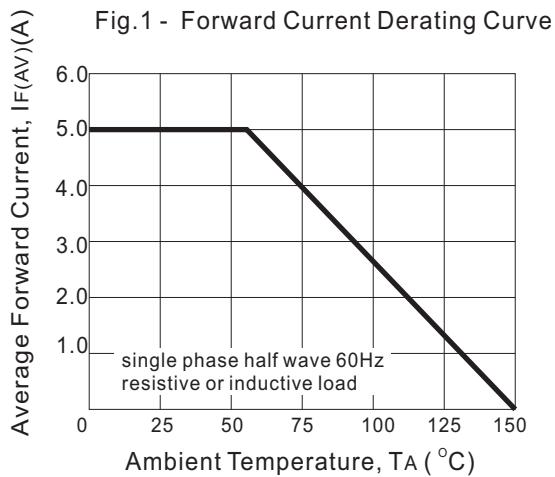
\*3 Continuous reverse voltage

\*4 Maximum forward voltage@ $I_F=5.0\text{A}$

\*5 Maximum Reverse recovery time, note 1

Note 1. Reverse recovery time test condition,  $I_F=0.5\text{A}$ ,  $I_R=1.0\text{A}$ ,  $I_{RR}=0.25\text{A}$

### Rating and characteristic curves



**Fig. 6 - Test Circuit Diagram and Reverse Recovery Time Characteristic**

